

**A new measure for calculating multiple fault coverage of microprocessor self-test**

**Oyeniran, Adeboye Stephen; Odozi, Uzochukwu Eddie; Ubar, Raimund-Johannes** BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill [http://www.estet.ee/record=b2150914\\*est](http://www.estet.ee/record=b2150914*est)

**High-level test data generation for software based self-test in microprocessors**

**Oyeniran, Adeboye Stephen; Jasnetski, Artjom; Tšertov, Anton; Ubar, Raimund-Johannes** 2017 6th Mediterranean Conference on Embedded Computing (MECO) : including ECYPS'2017 : proceedings : research monograph : Bar, Montenegro, June 11th-15th, 2017 2017 / p. 86-91 : ill <https://doi.org/10.1109/MECO.2017.7977167>

**Software-based self-test generation for microprocessors with high-level decision diagrams**

**Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton; Brik, Marina** Proceedings of the Estonian Academy of Sciences 2014 / p. 48-61 : ill [https://artiklid.elnet.ee/record=b2665215\\*est](https://artiklid.elnet.ee/record=b2665215*est)

**Teaching digital system test**

**Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Kruus, Margus** The 27th EAEEIE Annual Conference : June 7-9, 2017, Grenoble 2017 / [6] p